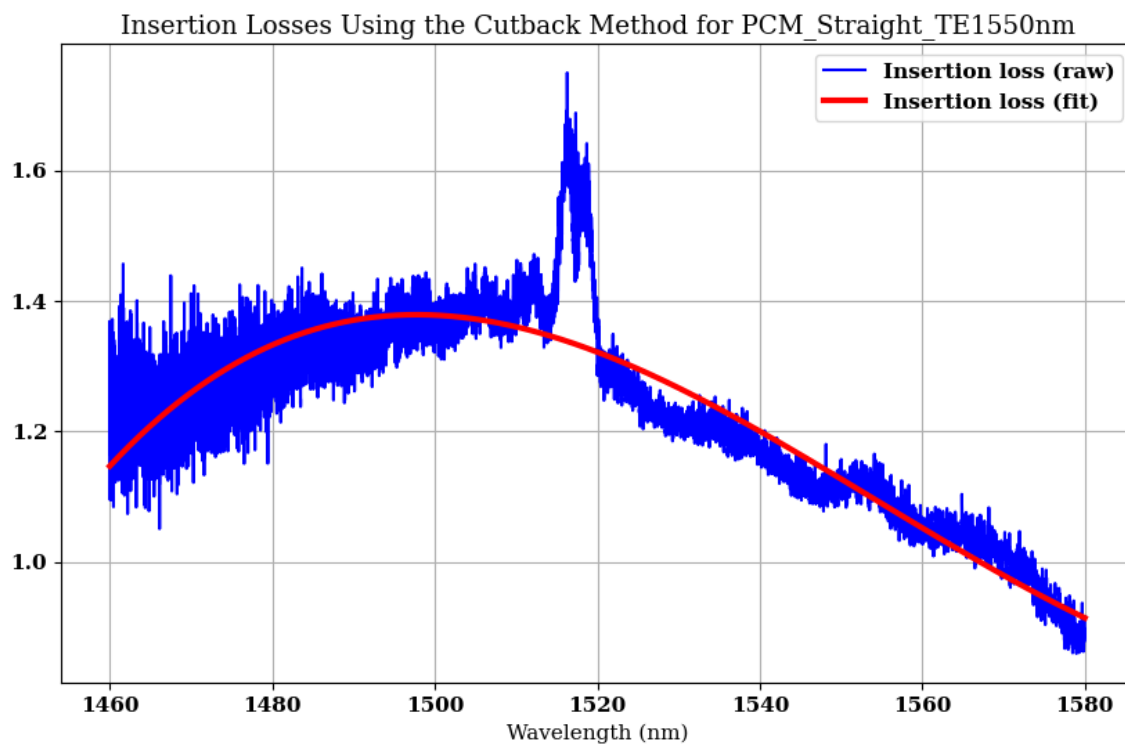
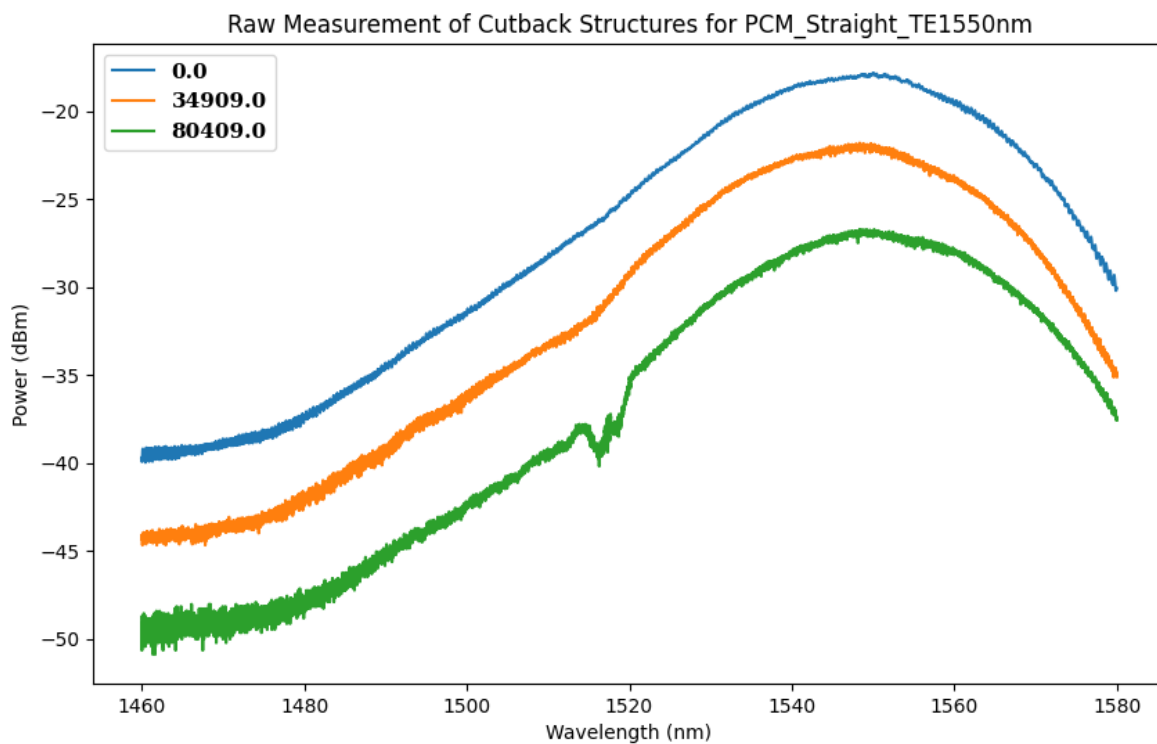


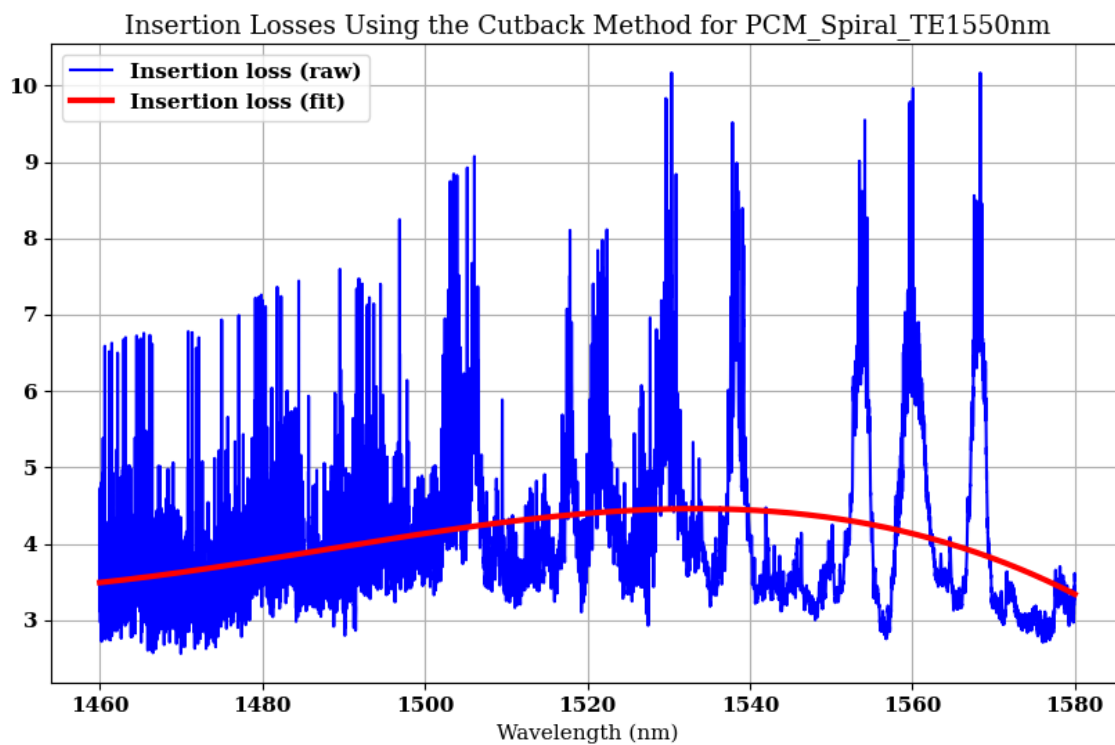
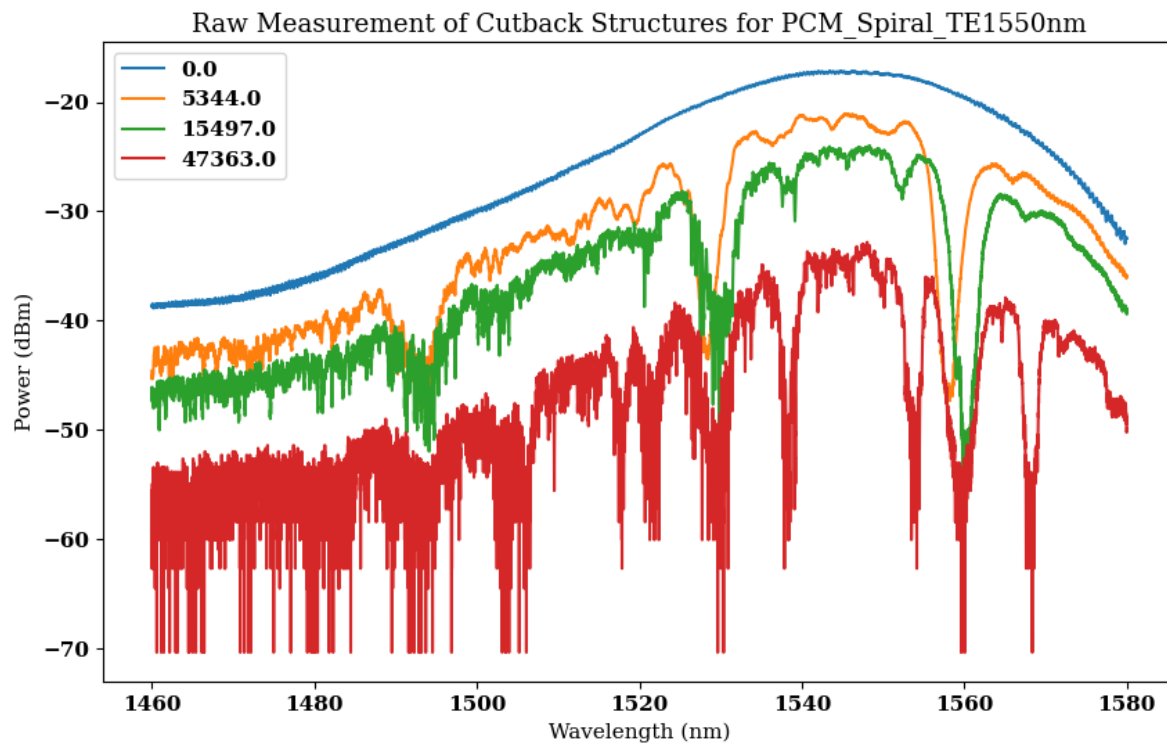
Analysis Report of EdX_May_2023_1550TE chip

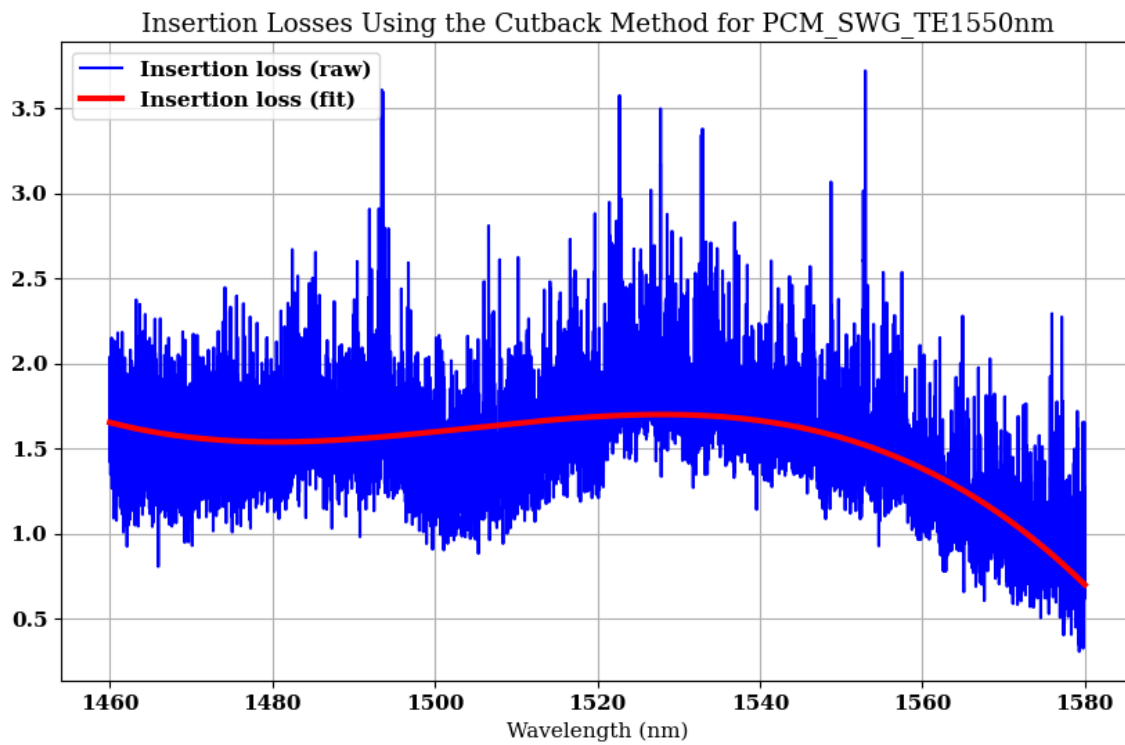
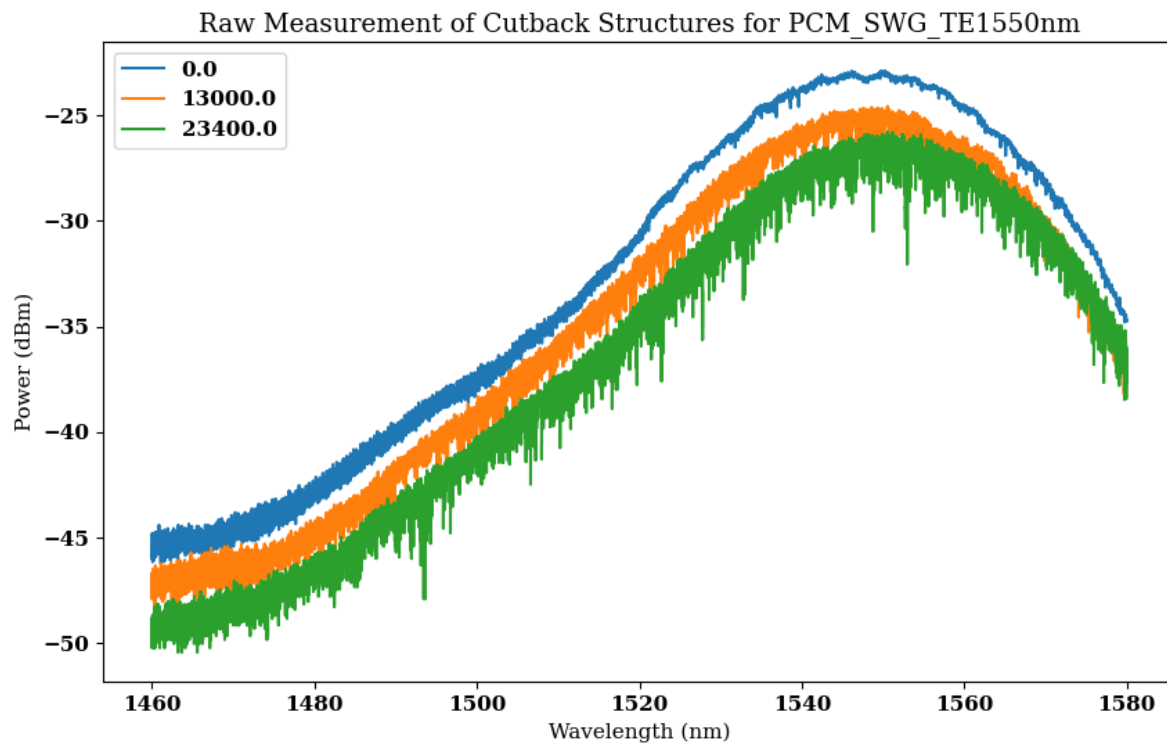
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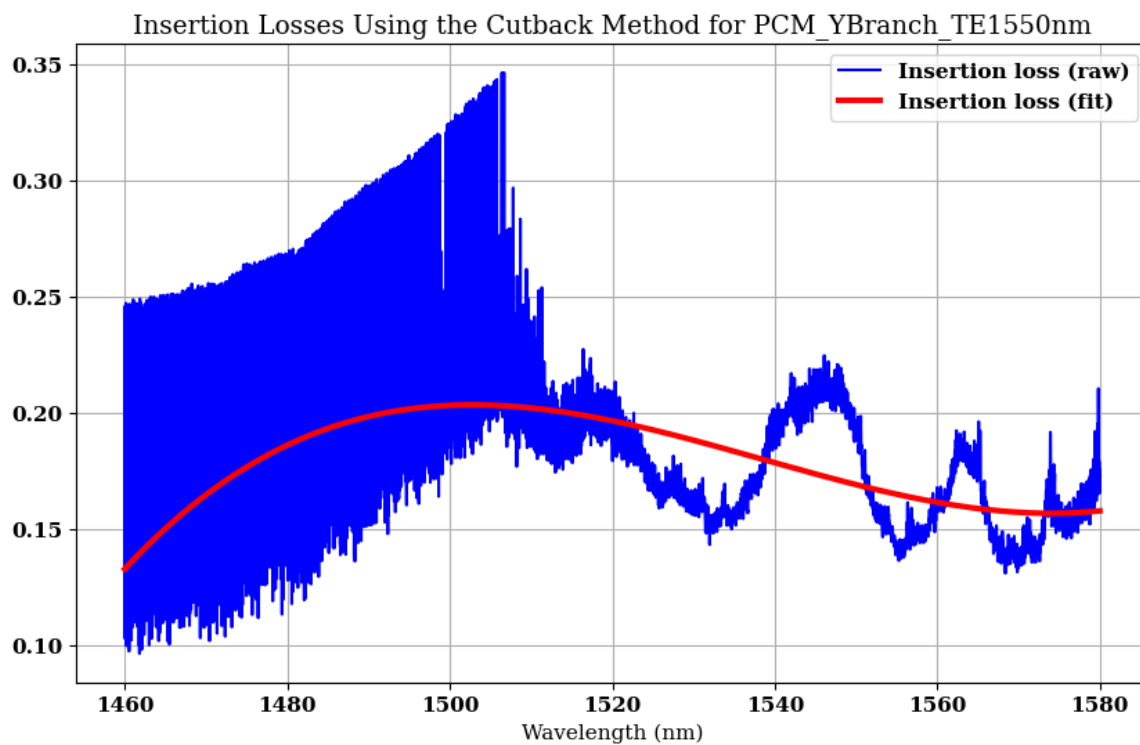
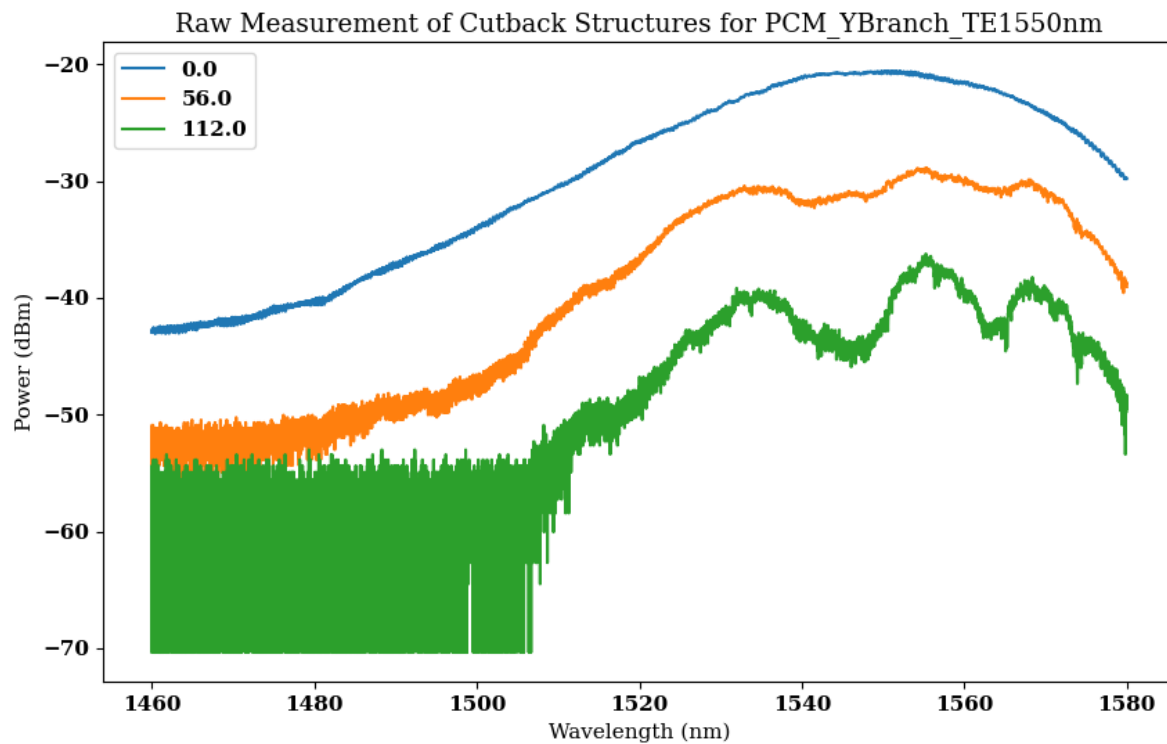
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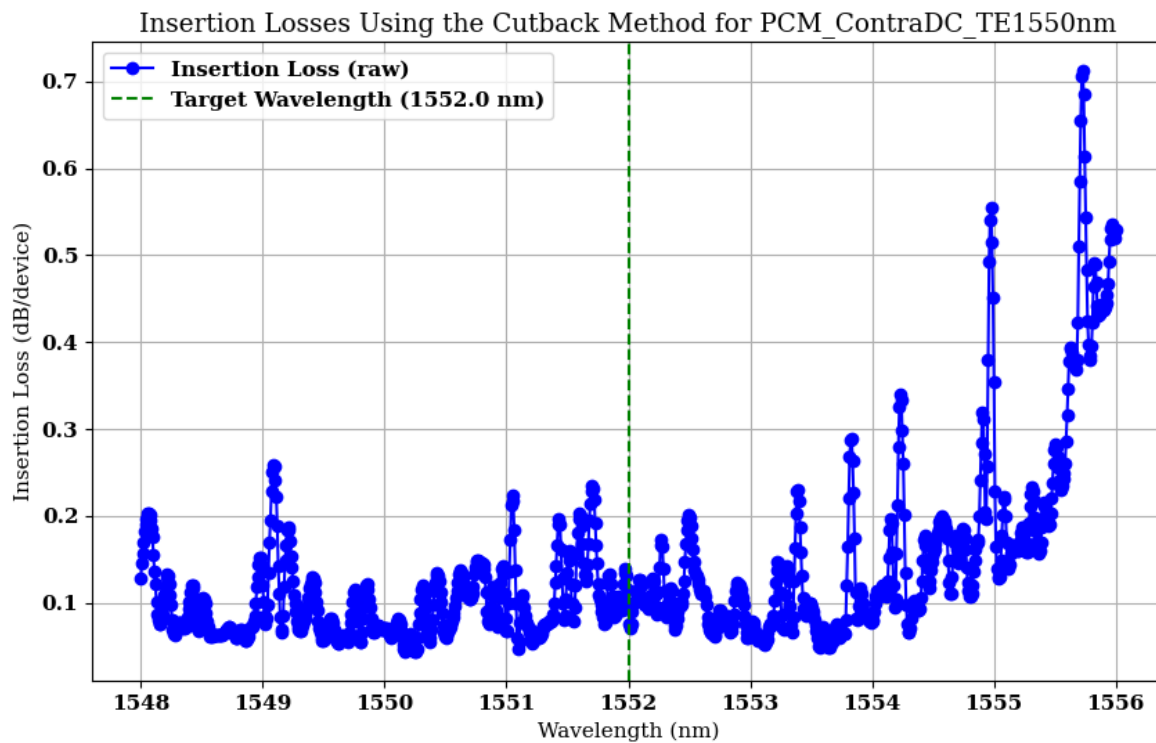
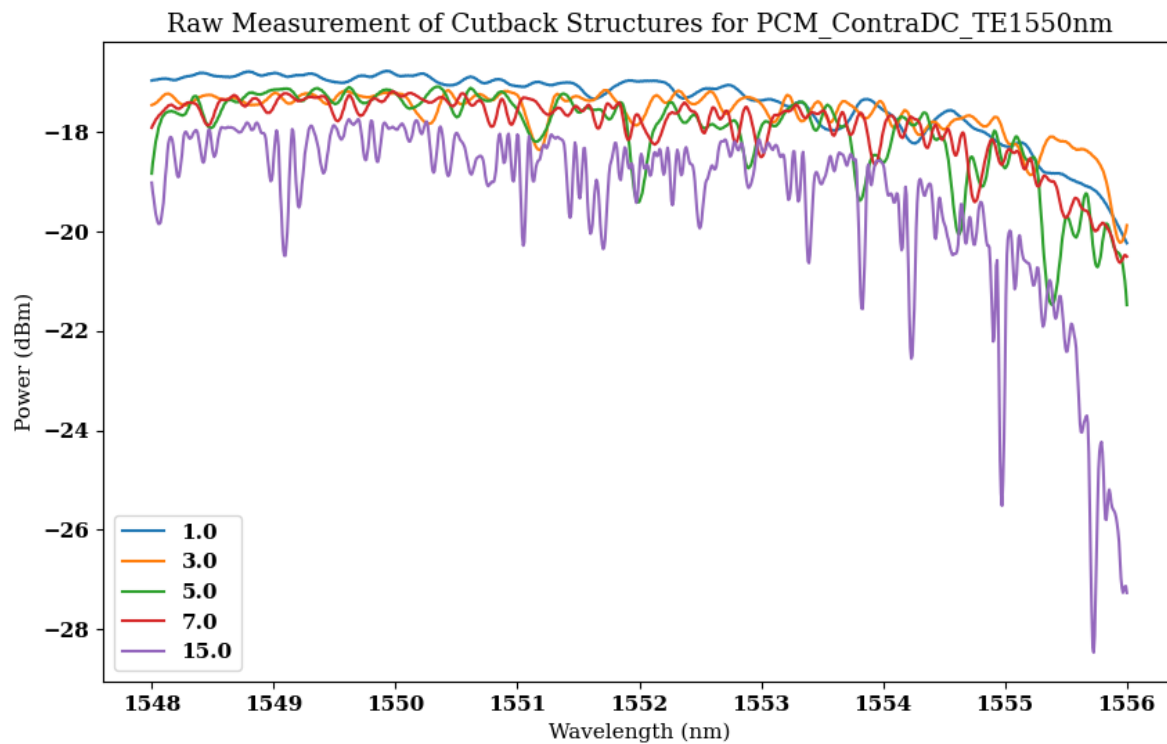
Name	Wavelength	Polarization	Data	Error	Analysis
PCM_Straight	1550nm	TE	1.13	0.0	Insertion Loss (dB/cm)
PCM_Spiral	1550nm	TE	4.34	0.65	Insertion Loss (dB/cm)
PCM_SWG	1550nm	TE	1.56	0.22	Insertion Loss (dB/cm)
PCM_YBranch	1550nm	TE	0.17	0.03	Insertion Loss (dB/device)
PCM_ContraDC	1550nm	TE	0.09	0.03	Insertion Loss (dB/device)
PCM_Bragg_Period	1550nm	TE	-4.72	N/A	Bragg Drift (nm)
PCM_Bragg_dW	1550nm	TE	N/A	N/A	Bragg Drift (nm)
PCM_GIndex	1550nm	TE	4.15	0.09	Group Index



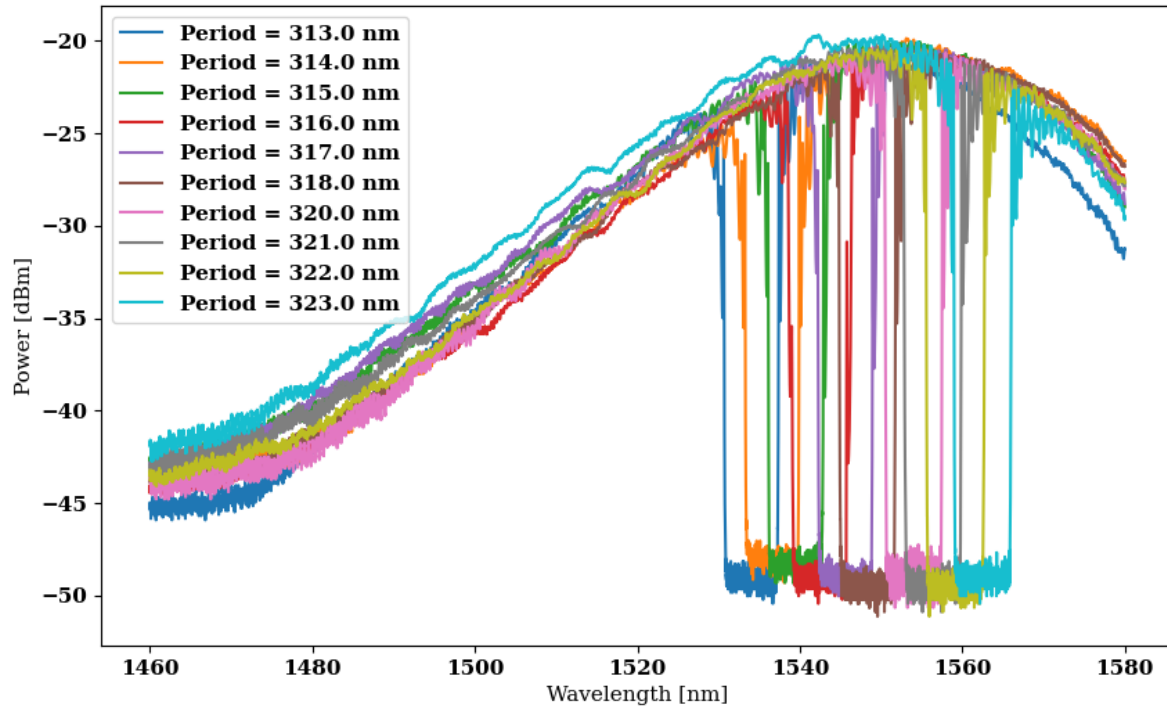




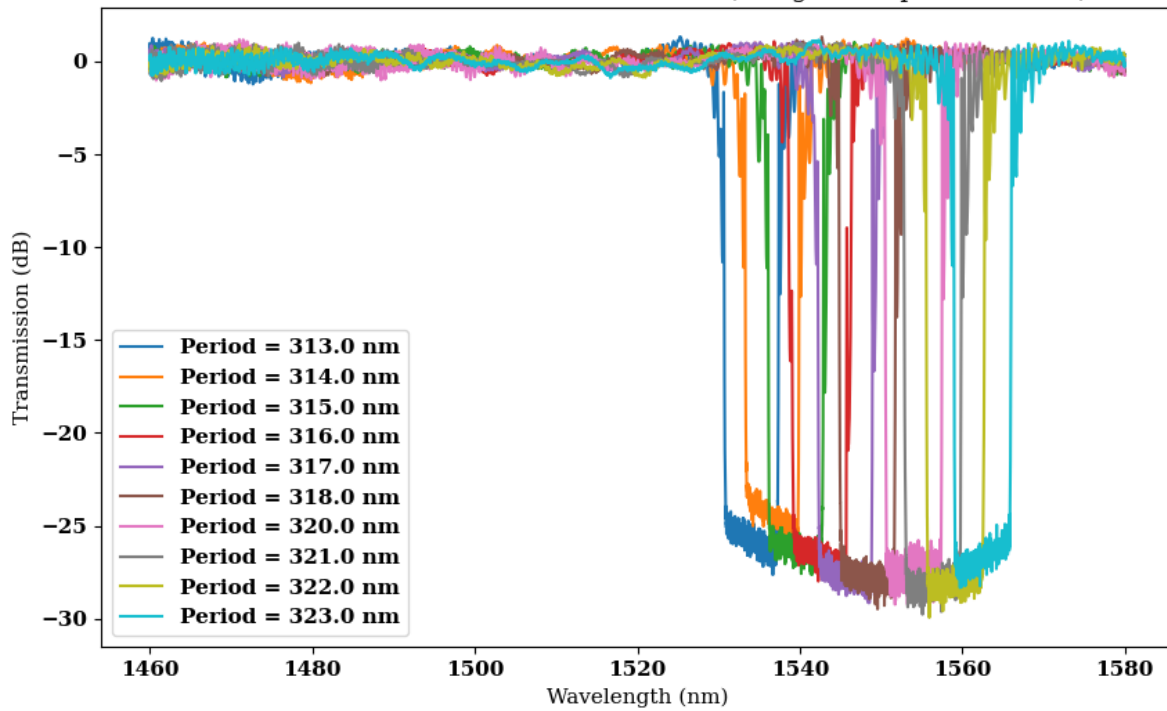


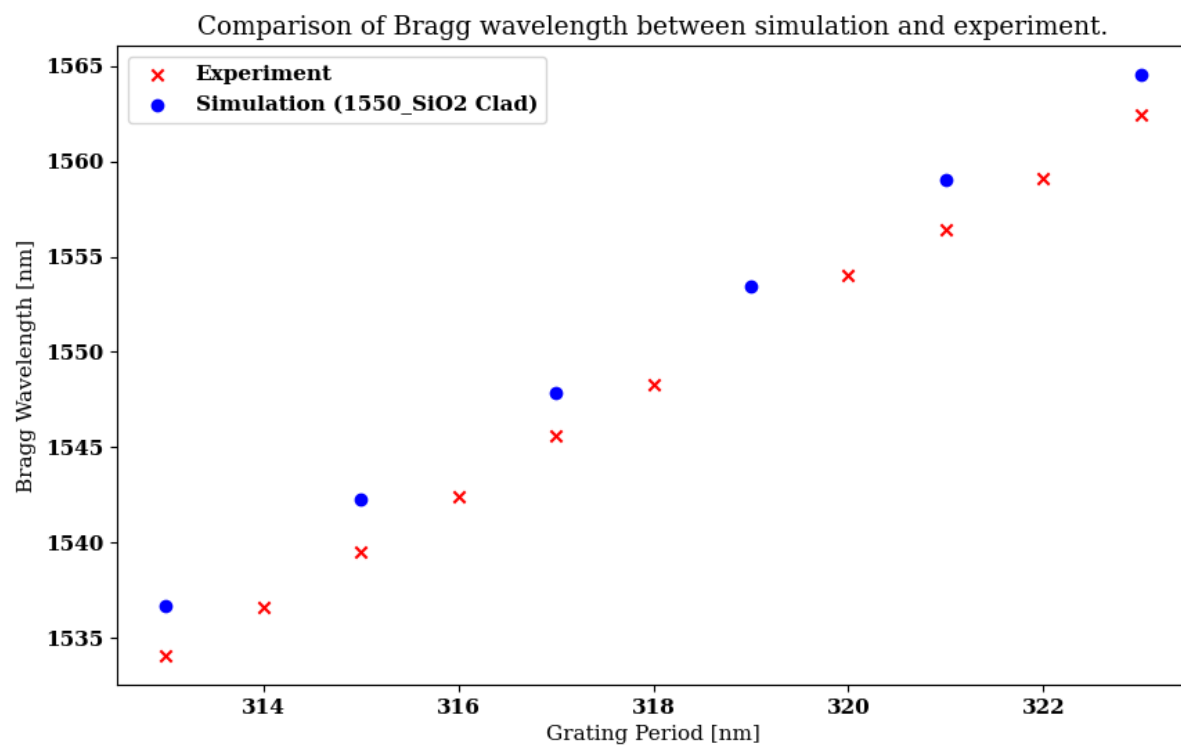
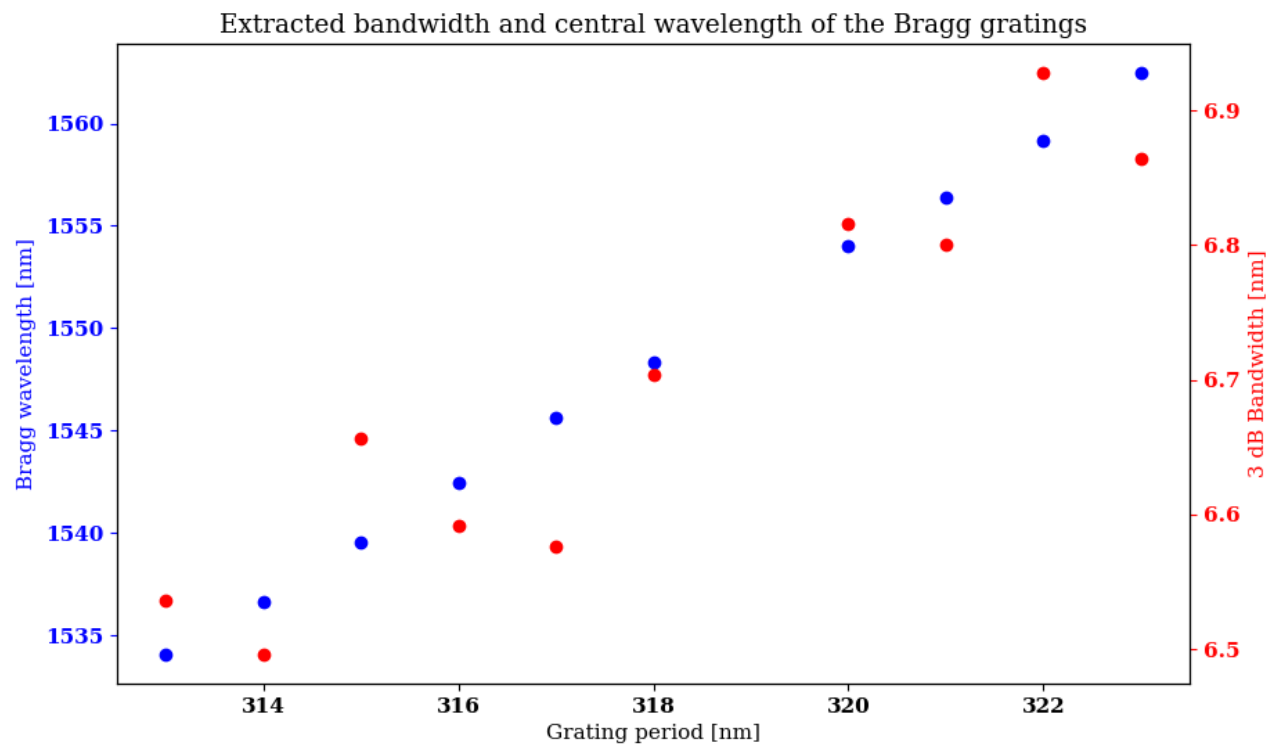


Raw measurement of all structures

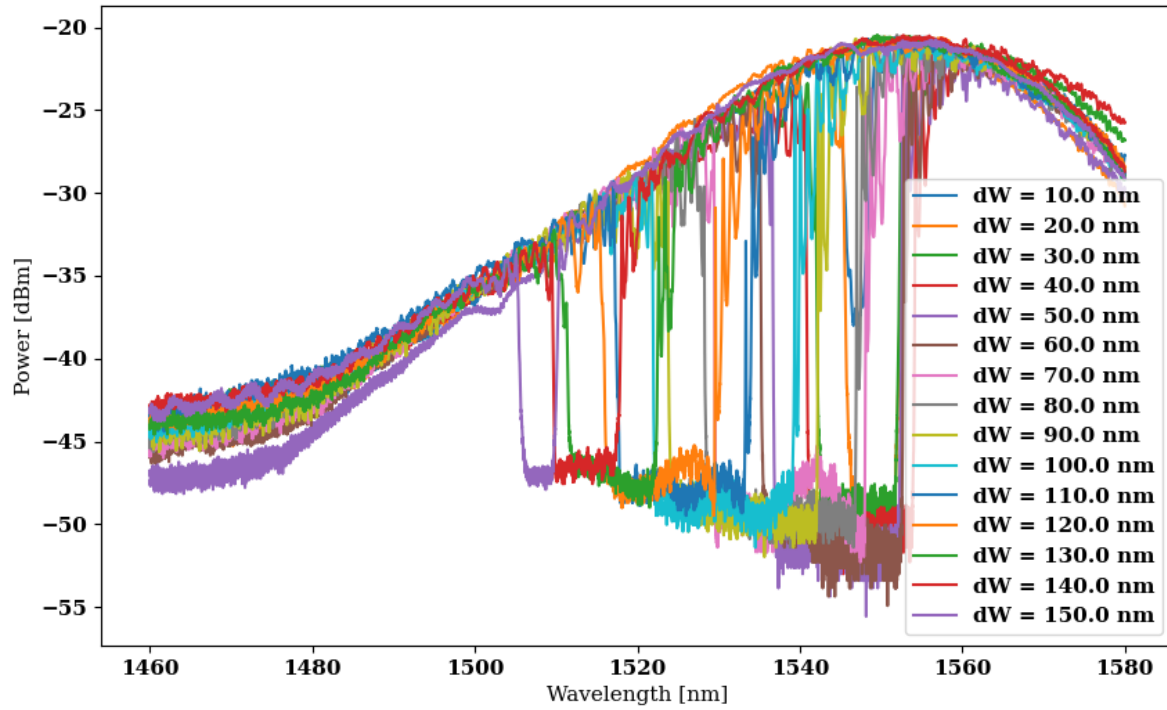


Calibrated measurement of all structures (using envelope calibration)





Raw measurement of all structures



Calibrated measurement of all structures (using envelope calibration)

